***Name and Address*:**

Laboratory name	**QCC Hazorea Calibration Technologies (A.C.S) Ltd.**
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Schedule of Accreditation

Item	*Scope Type*	*Site*	*Measurand Instrument, Gauge*		*Range [Including margins] (Does not include margins)*	*CMC Expressed as an Expanded Uncertainty (95%)*	*Reference Documents*	*Remarks*
Calibration – Electrical Quantities - DC and LF						*כיול – גדלים חשמליים - זרם ישר ותדר נמוך*		
1	A	P	DC Voltage, Sources	זרם ישר מחוללי מתח	± 1.018 V	6.5 µV/V	MetCal Automated Calibration Software Manufacturer instructions WI-C104 WI-C100 WI-C103	Wavetek 9100 Datron 1281 Wavetek 4808 Wavetek 4912 Wavetek 4950 Fluke 5520A Fluke 734A Fluke 5730A Fluke 8508A
2	A	P			± 10 V	5.7 µV/V		
3	A	P;T			0 mV	0.12 µV		
4	A	P			(0.1 µV to 200 mV]	6.81 µV/V		
5	A	P			(200 mV to 2 V]	3.74 µV/V		
6	A	P			(2V to 20 V]	3.66 µV/V		
7	A	P			(20 V to 200 V]	5.22 µV/V		
8	A	P			(200 V to 1050 V]	5.40 µV/V		
9	A	T			(0.1 µV to 200 mV]	14 µV/V		
10	A	T			(200 mV to 1V]	6.7 µV/V		
11	A	T			(1 V to 10 V]	5 µV/V		
12	A	T			(10 V to 100 V]	5 µV/V		
13	A	T			(100 V to 1000 V]	8.3 µV/V		
14	A	P,T	DC Voltage, Measuring Instruments	זרם ישר מכשירי מדידת מתח	0 mV	0.5 µV	MetCal Automated Calibration Software Manufacturer instructions WI-C100 WI-C103	Fluke 734A Wavetek 4912 Wavetek 4808 Datron 1281 Wavetek 4950 Fluke 5520A Wavetek 9100 Fluke 5730A
15	A	P			(0.1 µV to 220 mV]	14.3 µV/V		
16	A	P			(0.22 V to 2.2 V]	6.8 µV/V		
17	A	P			(2.2 V to 11 V]	4.5 µV/V		
18	A	P			(11 V to 22 V]	4.4 µV/V		
19	A	P			(22 V to 220 V]	6.4 µV/V		
20	A	P			(220 V to 1100 V]	8.7 µV/V		

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

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Calibration – Electrical Quantities - DC and LF						*כיול – גדלים חשמליים - זרם ישר ותדר נמוך*		
21	A	T			(0 mV to 329.9999 mV]	8.4 µV/V		Fluke 8508A
22	A	T			(329.9999 mV to 3.299999 V]	15 µV/V		
23	A	T			(3.299999 V to 32.99999 V]	16 µV/V		
24	A	T			(32.99999 V to 329.999 V]	26 µV/V		
25	A	T			(329.9999 V to 1000 V]	26 µV/V		
26	A	P;T	DC Current. Sources	זרם ישר, מחוללים	0 µA	0.6 nA	MetCal Automated Calibration Software Manufacturer instructions WI-C100	Datron 1281 Current clamp Fluke 337 Fluke 5730A Fluke 8508A
27	A	P;T			(10 nA to 200 µA]	14.32 µA/A		
28	A	P;T			(200 µA to 2 mA]	14.4 µA/A		
29	A	P;T			(2 mA to 20 mA]	1.49 µA/A		
30	A	P;T			(20 mA to 200 mA]	47.78 µA/A		
31	A	P;T			(200 mA to 2 A]	2.15 µA/A		
32	A	P;T			(2 A to 20 A]	48.7 µA/A		
33	A	P;T	DC Current, Measuring Instruments	זרם ישר, מכשירי מדידת זרם	0 µA	0.007 µA	MetCal Automated Calibration Software Manufacturer instructions WI-C100	Standard resistors Datron 1281 Wavetek 9100 Wavetek 4808 Wavetek 4950 Fluke 5520A
34	A	P;T			(2 nA to 220 µA]	120 µA/A		
35	A	P;T			(220 µA to.2 2 mA]	57 µA/A		
36	A	P;T			(2.2 mA to 22 mA]	52 µA/A		
37	A	P;T			(22 mA to 220 mA]	61 µA/A		
38	A	P;T			(220 mA to 2.2 A]	110 µA/A		
39	A	P;T			(2.2 A to 20 A]	480 µA/A		

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Calibration – Electrical Quantities - DC and LF						*כיול – גדלים חשמליים - זרם ישר ותדר נמוך*		
40	A	P;T			(20 A to 105 A]	0.64 mA/A		Fluke 5725A
41	A	P;T			(105 A to 160 A]	9.64 mA/A		Current Coils
42	A	P;T			(160 A to 525 A]	32.2 mA/A		Fluke 5730A
43	A	P;T			(525 A to 1000 A]	74.8 mA/A		Fluke 8508A
			AC Voltage,	מתח חילופין	(0.2 mV to 200 mV]			Datron 1281
44	A	P;T	Sources	מחוללים מתח	[1 Hz to 10 Hz]	127.5 µV/V	MetCal	Wavetek 4950
45	A	P;T			(20 Hz to 40 Hz]	125.3 µV/V		FLUKE 5730A
46	A	P;T			(40 Hz to 100Hz]	124.9 µV/V	Automated	FLUKE 8508A
47	A	P;T			(100Hz to 2 kHz]	124.7 µV/V	Calibration Software Manufacturer instructions	
48	A	P;T			(2 kHz to 10 kHz]	124.9 µV/V	WI-C100	*Traceable but not accredited.
49	A	P;T			(10 kHz to 30 kHz]	131.7 µV/V	WI-C106	
50	A	P;T			(30 kHz to 100 kHz]	2.66 mV/V		
					(200 mV to 2 V]			
51	A	P;T			[1 Hz to 10 Hz]	162 µV/V		
52	A	P;T			(20 Hz to 40 Hz]	128.3 µV/V		
53	A	P;T			(40 Hz to 100Hz]	116.9 µV/V		
54	A	P;T			(100Hz to 2 kHz]	93.8 µV/V		
55	A	P;T			(2 kHz to 10 kHz]	116.6 µV/V		
56	A	P;T			(10 kHz to 30 kHz]	310.5 µV/V		

Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 014

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Calibration – Electrical Quantities - DC and LF						*כיול – גדלים חשמליים - זרם ישר ותדר נמוך*		
57	A	P;T			(30 kHz to 100 kHz]	889.3 µV/V		
58	A	P;T			(100 kHz to 300kHz]	889.3 µV/V		
59	A	P;T			(300 kHz to 1MHz]	34.6 mV/V		
					(2 V to 20V]			
60	A	P;T			[1 Hz to 10 Hz]	1.58 mV/V		
61	A	P;T			(20 Hz to 40 Hz]	1.57 mV/V		
62	A	P;T			(40 Hz to 100Hz]	1.17 mV/V		
63	A	P;T			(100Hz to 2 kHz]	0.93 mV/V		
64	A	P;T			(2 kHz to 10 kHz]	1.17 mV/V		
65	A	P;T			(10 kHz to 30 kHz]	2.77 mV/V		
66	A	P;T			(30 kHz to 100 kHz]	8.1 mV/V		
67	A	P;T			(100 kHz to 300kHz]	57.8 mV/V		
68	A	P;T			(300 kHz to 1MHz]	346.47 mV/V		
					(20V to 200V]			
69	A	P;T			[1 Hz to 10 Hz]	16 mV/V	MetCal	Datron 1281
70	A	P;T			(20 Hz to 40 Hz]	13.15 mV/V		Wavetek 4950
71	A	P;T			(40 Hz to 100Hz]	12.1 mV/V	Automated Calibration Software	FLUKE 5730A FLUKE 8508A
72	A	P;T			(100Hz to 2 kHz]	10.8 mV/V	Manufacturer instructions	
73	A	P;T			(2 kHz to 10 kHz]	11.9 mV/V	WI-C100	
74	A	P;T			(10 kHz to 30 kHz]	11.9 mV/V	WI-C106	*Traceable but not

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Calibration – Electrical Quantities - DC and LF						*כיול – גדלים חשמליים - זרם ישר ותדר נמוך*		
75	A	P;T			(30 kHz to 100 kHz]	81 mV/V		accredited.
76	A	P;T			(100 kHz to 300kHz]	577.37 mV/V		
77	A	P;T			*(300 kHz to 1MHz]	3465 mV/V		
					(200 V to 1050 V]			
78	A	P;T			*[1 Hz to 40 Hz]	141 mV/V		
79	A	P;T			(40 Hz to 10kHz]	73.4 mV/V		
80	A	P;T			(10kHz to 30 kHz]	162 mV/V		
81	A	P;T			*(30 kHz to 100 kHz]	520 mV/V		
			AC Voltage. Measuring Instruments	מתח חילופין מכשירי מדידת מתח	(0.2 mV to 220 mV]		MetCal Automated Calibration Software Manufacturer instructions WI-C100 WI-C102 WI-C105	Datron 1281 Wavetek 9100 Wavetek 4808 Wavetek 4950 Fluke 5520A FLUKE 5730A FLUKE 8508A
82	A	P;T			(10Hz to 20 Hz]	431 µV/V		
83	A	P;T			(20 Hz to 40 Hz]	204 µV/V		
84	A	P;T			(40 Hz to 20 kHz]	162 µV/V		
85	A	P;T			(20 kHz to 50 kHz]	230 µV/V		
86	A	P;T			(50 kHz to 100 kHz]	566 µV/V		
87	A	P;T			(100 kHz to 300 kHz]	1.1 mV/V		

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Calibration – Electrical Quantities - DC and LF							***כיול – גדלים חשמליים - זרם ישר ותדר נמוך***
88	A	P;T		(300 kHz to 500 kHz]	2.0 mV/V		*Traceable but not accredited.
89	A	P;T		(500 kHz to 1 MHz]	3.9 mV/V		
				(220 mV to 2.2 V]			
90	A	P;T		(10Hz to 20 Hz]	325 µV/V		
91	A	P;T		(20 Hz to 40 Hz]	134 µV/V		
92	A	P;T		(40 Hz to 20 kHz]	62 µV/V		
93	A	P;T		(20 kHz to 50 kHz]	93 µV/V		
94	A	P;T		(50 kHz to 100 kHz]	136 µV/V		
95	A	P;T		(100 kHz to 300 kHz]	489 µV/V		
96	A	P;T		(300 kHz to 500 kHz]	1.5 mV/V		
97	A	P;T		(500 kHz to 1 MHz]	2.7 mV/V	MetCal Automated Calibration Software Manufacturer instructions WI-C100 WI-C102 WI-C105	
				(2.2 V to 22 V]			
98	A	P;T		(10Hz to 20 Hz]	331 µV/V		
99	A	P;T		(20 Hz to 40 Hz]	128 µV/V		
100	A	P;T		(40 Hz to 20 kHz]	60 µV/V		
101	A	P;T		(20 kHz to 50 kHz]	95 µV/V		
102	A	P;T		(50 kHz to 100 kHz]	132 µV/V		

Schedule of Accreditation

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Calibration – Electrical Quantities - DC and LF								*כיול – גדלים חשמליים - זרם ישר ותדר נמוך*
103	A	P;T			(100 kHz to 300 kHz]	430 µV/V		
104	A	P;T			(300 kHz to 500 kHz]	1.5 mV/V		
105	A	P;T			(500 kHz to 1 MHz]	2.7 mV/V		
					(22 V to 220 V]			
106	A	P;T			(10Hz to 20 Hz]	299 µV/V		
107	A	P;T			(20 Hz to 40 Hz]	122 µV/V		
108	A	P;T			(40 Hz to 20 kHz]	81 µV/V		
109	A	P;T			(20 kHz to 50 kHz]	105 µV/V		
110	A	P;T			(50 kHz to 100 kHz]	187 µV/V		
111	A	P;T			(100 kHz to 300 kHz]	1.1 mV/V		
112	A	P;T			(300 kHz to 500 kHz]	5.1 mV/V		
113	A	P;T			(500 kHz to 1 MHz]	9.3 mV/V		
114	A	P;T			(220 V to 1100 V] (15 Hz to 50 Hz]	348 µV/V		
115	A	P;T			(50 Hz to 1kHz]	84 µV/V	Manufacturer instructions WI-C100	
116	A	P;T	AC Current Sources	זרם חילופין מחוללי זרם	(200 µA to 2 mA] *[1 Hz to 10 Hz]	524 µA/A	MetcalAutomated Calibration Software Manufacturer Instruction WI-C100	Datron 1281 Wavetek 4950 Fluke 337

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Calibration – Electrical Quantities - DC and LF							***כיול – גדלים חשמליים - זרם ישר ותדר נמוך***
117	A	P;T		[10 Hz to 10 kHz]	523 µA/A		Fluke 5780A Fluke 5725A Fluke 8508A
118	A	P;T		(10 kHz to 30 kHz]	929 µA/A		
119	A	P;T		*(30 kHz to 100 kHz]	0.93 mA/A		
				(2 mA to 20 mA]			
120	A	P;T		*[1 Hz to 10 Hz]	521 µA/A		
121	A	P;T		[10 Hz to 10 kHz]	521 µA/A		
122	A	P;T		(10 kHz to 30 kHz]	925 µA/A		
123	A	P;T		*(30 kHz to 100 kHz]	4.85 mA/A		
				(20 mA to 200 mA]			
124	A	P;T		*[1 Hz to 10 Hz]	26.64 µA/A		
125	A	P;T		[10 Hz to 10 kHz]	522 µA/A		
126	A	P;T		*(10 kHz to 30 kHz]	925 µA/A		
				(200 mA to 2 A]			
127	A	P;T		(10 Hz to 2 kHz]	925 µA/A		
128	A	P;T		(2 kHz to 10 kHz]	1040 µA/A		

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Calibration – Electrical Quantities - DC and LF								*כיול – גדלים חשמליים - זרם ישר ותדר נמוך*
129	A	P;T			(10 kHz to 30 kHz]	3.71 mA/A		
					(2 A to 20 A]			
130	A	P;T			(10 Hz to 2 kHz]	1.2 mA/A		
131	A	P;T			(2kHz to 10kHz]	3.2mA/A		
	A	P;T	AC Current	זרם חילופין	(0.1 µA to 220 µA]		MetCal	Datron 1281
132	A	P;T	Measuring Instruments	מכשירי מדידה	[10 Hz to 20Hz]	487 µA/A	MTS Automated	Wavetek 9100
133	A	P;T			[20 Hz to 40Hz]	314 µA/A	Calibration Software	Wavetek 4808
							Manufacturer instructions	Wavetek MTS 4950
134	A	P;T			[40 Hz to 1 kHz]	223 µA/A	WI-C100	Fluke 5520A Fluke 5720A
135	A	P;T			[1 kHz to 5 kHz]	525 µA/A	WI-C102	Current Coils
136	A	P;T			(5 kHz to 10 kHz]	2.2 mA/A		
137	A	P;T			(220 µA to 2.2 mA]			
					[10 Hz to 20Hz]	347 µA/A		
138	A	P;T			[20 Hz to 40Hz]	238 µA/A		
139	A	P			[40 Hz to 1 kHz]	170 µA/A		
140	A	P;T			[1 kHz to 5 kHz]	340 µA/A		
141	A	P			(5 kHz to 10 kHz]	2.1 mA/A		

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Calibration – Electrical Quantities - DC and LF					*כיול – גדלים חשמליים - זרם ישר ותדר נמוך*		
				(2.2 mA to 22 mA]			
142	A	P;T		[10 Hz to 20Hz]	363 µA/A		
143	A	P;T		[20 Hz to 40Hz]	245 µA/A		
144	A	P;T		[40 Hz to 1 kHz]	178 µA/A		
145	A	P;T		[1 kHz to 5 kHz]	365 µA/A		
146	A	P;T		(5 kHz to 10 kHz]	1.95 mA/A		
				(22 mA to 220 mA]			
147	A	P;T		[10 Hz to 20Hz]	360 µA/A		
148	A	P;T		[20 Hz to 40Hz]	243 µA/A		
149	A	P;T		[40 Hz to 1 kHz]	171 µA/A		
150	A	P;T		[1 kHz to 5 kHz]	321 µA/A		
151	A	P;T		(5 kHz to 10 kHz]	1.6 mA/A		
				(220 mA to 2.2 A]			
152	A	P;T		[20 Hz to 1 kHz]	344 µA/A		
153	A	P;T		(1 kHz to 5 kHz]	674 µA/A		
154	A			(5 kHz to 10 kHz]	8.4 mA/A		
155	A	P;T		(2.2 A to 11 A] (40 Hz to 1 kHz]	558 µA/A		

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Calibration – Electrical Quantities - DC and LF						*כיול – גדלים חשמליים - זרם ישר ותדר נמוך*		
156	A	P;T			(1 kHz to 5 kHz]	1.2 mA/A		
157	A	P;T			(5 kHz to 10 kHz]	4.3 mA/A		
158	A	P;T			(11 A to 20.5 A] (45 Hz to 100 Hz]	7.23 mA/A		
159	A	P;T			(100Hz to 1 kHz]	7.6 mA/A		
160	A	P;T			(1 kHz to 5 kHz]	41 mA/A		
161	A	P;T			(20 A to 32 A] (10 Hz to 440 Hz]	8.2 mA/A		
162	A	P;T			(32 A to 160 A] [10 Hz to 100 Hz]	39 mA/A		
163	A	P;T			(160 A to 200 A] (10 Hz to 440 Hz]	68 mA/A		
164	A	P;T			(200 A to 1000 A] [10 Hz to 50 Hz]	195 mA/A		
165	A	P;T	DC Resistance, Resistors Shunts	התנגדות זרם ישר, נגדים מיצד זרם	0.0001 Ω	160 mΩ/Ω	Manufacturer instructions WI-C100 WI-C101 WI-C103	DMM 1281A DMM 34401A FLUKE 8508A DMM 6.5digit
166	A	P;T			0.0002 Ω	79 mΩ/Ω		
167	A	P;T			0.0005 Ω	31 mΩ/Ω		
168	A	P;T			0.005 Ω	310 µΩ/Ω		
169	A	P;T			0.001 Ω	1.54 mΩ/Ω		
170	A	P;T			0.01 Ω	1.5 mΩ/Ω		
171	A	P;T			0.1 Ω	2.3 mΩ/Ω		
172	A	P;T			0 Ω	5 µΩ		

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Calibration – Electrical Quantities - DC and LF						*כיול – גדלים חשמליים - זרם ישר ותדר נמוך*		
173	A	P;T			1 Ω	1.6 mΩ/Ω		
174	A	P;T			1.9 Ω	1.41 mΩ/Ω		
175	A	P;T			10 Ω	1 mΩ/Ω		
176	A	P;T			19 Ω	0.9 mΩ/Ω		
177	A	P;T			50 Ω	952 µΩ/Ω		
178	A	P;T			100 Ω	910 µΩ/Ω		
179	A	P;T			190 Ω	870 µΩ/Ω		
180	A	P;T			1 kΩ	9.01 µΩ/Ω		
181	A	P;T			1.9 kΩ	17 µΩ/Ω		
182	A	P;T			10 kΩ	89.4 µΩ/Ω		
183	A	P;T			50 kΩ	168.9 µΩ/Ω		
184	A	P;T			100 kΩ	0.92 mΩ/Ω	Manufacturer instructions WI-C100 WI-C101 WI-C103	
185	A	P;T			190 kΩ	1.69 mΩ/Ω		
186	A	P;T			1 MΩ	10.9 µΩ/Ω		
187		P,T			1.9 MΩ	19 µΩ/Ω		

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Calibration – Electrical Quantities - DC and LF						***כיול – גדלים חשמליים - זרם ישר ותדר נמוך***		
188	A	P;T			10 MΩ	251 µΩ/Ω		
189	A	P;T			19 MΩ	351 µΩ/Ω		
190	A	P;T			100 MΩ	4.65 mΩ/Ω		
191	A	P;T			1 GΩ	317 µΩ/Ω		
192	A	P;T			[High Amp. Std. Shunt] 0.0005Ω÷0.5 Ω @ 141A	0.016%	Manufacturer instructions WI-C101	
193	A	P;T			0.0005Ω÷0.5 Ω @ 224A	0.016%		
194		P,T			0.0005Ω÷0.5 Ω @ 300A	0.016%		
195	A	P;T			0.0001Ω÷0.5 Ω @ 10A÷300A	0.11%		

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Calibration – Electrical Quantities - DC and LF						***כיול – גדלים חשמליים - זרם ישר ותדר נמוך***		
196	A	P;T	DC Resistance, Sources	התנגדות זרם ישר, מחוללים	(0 Ω to 2 G Ω] (0 Ω to 2 Ω]	17 µΩ/Ω + 4µΩ	MetCal Automated Calibration Software Manufacturer instructions WI-C100 WI-C101 WI-C103	Wavetek 9100 Fluke 5522A Datron 1281 Wavetek 4808 Standard resistance Wavetek 4950 FLUKE 5730A FLUKE 8508A *Traceable but not Accredited
197	A	P;T			(2 Ω to 20 Ω]	9 µΩ/Ω		
198	A	P;T			(20 Ω to 200 Ω]	8.98 µΩ/Ω		
199	A	P;T			(200 Ω to 2 kΩ]	9.29 µΩ/Ω		
200	A	P;T			(2 kΩ to 20 kΩ]	9.22 µΩ/Ω		
201	A	P;T			(20 kΩ to 200 kΩ]	9.41 µΩ/Ω		
202	A	P;T			(200 kΩ to 2 MΩ]	11.5 µΩ/Ω		
203	A	P;T			(2 MΩ to 20 MΩ]	313 µΩ/Ω		
204	A	P;T			(20 MΩ to 200 MΩ]	6.9 mΩ/Ω		
205	A	P;T			(200 MΩ to 2 GΩ]	0.18%		
206	A	P;T			(2 GΩ to 100 GΩ]	0.18%		
207	A	P;T	DC Resistance, Measuring Instruments	התנגדות זרם ישר, מכשירי מדידה	(1 µΩ to 10 Ω]	21 µΩ/Ω	MetCal Automated Calibration Software Manufacturer instructions WI-C100 WI-C101	Wavetek 4950 Datron 1281 Wavetek 9100 QCC 23-135
208	A	P;T			(10 Ω to 100 Ω]	9 µΩ/Ω		
209	A	P;T			(100 Ω to 10 kΩ]	20 µΩ/Ω		
210	A	P;T			(10 kΩ to 100 kΩ]	8 µΩ/Ω		
211	A	P;T			(100 kΩ to 1 MΩ]	6 µΩ/Ω		
212	A	P;T			(1 MΩ to 10 MΩ]	30 µΩ/Ω		
213	A	P;T			(10 MΩ to 100 MΩ]	199 µΩ/Ω		
214	A	P;T			(100 MΩ to 1 GΩ]	517 µΩ/Ω		
215	A	P;T			(10 GΩ to 100 GΩ]	8.4 mΩ/Ω		

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Calibration – Electrical Quantities - DC and LF					*כיול – גדלים חשמליים - זרם ישר ותדר נמוך*			
216	A	P;T	Std Resistors, MFC source Measuring Instuments	נגדים סטנדרטיים כיילים רב-תחומיים מכשירי מדידה	1 Ω	7 µΩ/Ω	Manufacturer instructions WI-C100 WI-C101	
217	A	P;T			1.9 Ω	111 µΩ/Ω		
218	A	P;T			10 Ω	8 µΩ/Ω		
219	A	P;T			19 Ω	27 µΩ/Ω		
220	A	P;T			100 Ω	8 µΩ/Ω		
221	A	P;T			190 Ω	12 µΩ/Ω		
222	A	P;T			1 kΩ	8 µΩ/Ω		
223	A	P;T			1.9 kΩ	8 µΩ/Ω		
224	A	P;T			10 kΩ	3.5 µΩ/Ω		
225	A	P;T			19 kΩ	8 µΩ/Ω		
226	A	P;T			100 kΩ	13 µΩ/Ω		
227	A	P;T			190 kΩ	11 µΩ/Ω		
228	A	P;T			1 MΩ	16 µΩ/Ω		
229	A	P;T			1.9 MΩ	23 µΩ/Ω		
230	A	P;T			10 MΩ	47 µΩ/Ω		
231	A	P;T			19 MΩ	57 µΩ/Ω		
			Capacitance, Measuring Instruments	קיבול מכשירי מדידה	(0.5 nF to 4 nF] Up to 350 Hz]	247 µF/F	MetCal Automated	Wavetek 9100 Standard Capacitors Fluke 5520 A

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Calibration – Electrical Quantities - DC and LF							*כיול – גדלים חשמליים - זרם ישר ותדר נמוך*
232	A	P;T				Calibration Software Manufacturer instructions WI-C100	GR Capacitance Decade Standard Capacitors FLUKE 5502E FLUKE 5522A
233	A	P;T		(350 Hz to 1.5 kHz]	2.5 mF/F		
				(4 nF to 40 nF]			
234	A	P;T		Up to 350 Hz]	4.2 mF/F		
235	A	P;T		(350 Hz to 1.5 kHz]	4.2 mF/F		
				(40 nF to 400 nF]			
236	A	P;T		Up to 350 Hz]	15.6 mF/F		
237	A	P;T		(350 Hz to 1.5 kHz]	15.66 mF/F		
				(400 nF to 4 µF]			
238	A	P;T		Up to 350 Hz]	1.2 mF/F		
239	A	P;T		(350 Hz to 1.5 kHz]	1.2 mF/F		
				(4 µF to 40 µF]			
240	A	P;T		Up to 350 Hz]	769 µF/F		
241	A	P;T		(350 Hz to 1.5 kHz]	769 µF/F		
				(40 µF to 400 µF]			
242	A	P;T		Up to 350 Hz]	501 µF/F		
243	A	P;T		(350 Hz to 1.5 kHz]	501 µF/F		
				(400 µF to 4 mF]			
244	A	P;T		Up to 350 Hz]	1.2 mF/F		
245	A	P;T		(350 Hz to 1.5 kHz]	1.2 mF/F		
				(4 mF to 40 mF]		Manufacturer instructions	

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Calibration – Electrical Quantities - DC and LF						*כיול – גדלים חשמליים - זרם ישר ותדר נמוך*		
246	A	P;T			Up to 350 Hz]	1.2 mF/F	WI-C100	
247	A	P;T			(350 Hz to 1.5 kHz]	1.2 mF/F		
248	A	P;T	Capacitance, Capacitors	קיבול, קבלים	0.001 μF 1000 Hz	6 mF/F	Manufacturer instructions WI-C100	
249	A	P,T			0.005 μF 1000 Hz	262 μF/F		
250	A	P,T			0.01 μF 1000 Hz	595 μF/F		
251	A	P,T			0.05 μF 1000 Hz	137 μF/F		
252	A	P,T			0.1 μF 1000 Hz	92 μF/F		
253	A	P	Phase angle, Measurement Phase angle meters	זווית מופע מכשירי מדידה מדי זווית מופע	(0° to 90°) Frequency: [45 Hz to 65 Hz]	0.58°	Manufacturer Instructions WI-C108	FLUKE 5520AFLUKE 5522A Electrical test Equipment CALIBRATOR
254		P			Frequency: [65 Hz to 500 Hz] Parameters: V: 32 mV to 600 V I: 32 mA to 20 A Alternating V: 10 mV to 5 V When current transducer not allowed	0.21°	Manufacturer instructions WI-C108	

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Calibration – Electrical Quantities - DC and LF						*כיול – גדלים חשמליים - זרם ישר ותדר נמוך*		
255	A	P,T	AC Power, Measurement Power Meters	הספק מתח חילופין מדי הספק	[1mW to 20 kW] Power factor: [0– 1] Frequency: [45 Hz to 65Hz]	3.5 %	MetCal Automated Calibration Software Manufacturer instruction WI-C108	Fluke 5520A Fluke 5522A Electrical Test Equipment calibrator
256	A	P,T	Power factor, Measurement Power Meters	מקדם הספק מדידה מדי הספק	[0– 1] Power: [1mW to 20 kW] Frequency: [45 Hz to 65Hz]	0.14		
257	A	P,T	DC Power, Measurement Power Meters	הספק מתח ישר מדי הספק	[10 mW to 20 kW]	0.5 %		
258	A	P,T	Continuity resistance Resistance, measuring instruments	התנגדות רציפות, מכשירי מדידת התנגדות	0.20 Ω to 20 Ω	1.5%	MetCal Automated Calibration Software Manufacturer instructions WI-C107	TRANSMILLE 3200 Electrical Test Equipment Calibrator
259	A	P,T			20 Ω to 200 Ω	1.2%		
260	A	P,T			200 Ω to 2 kΩ	1.2%		
261	A	P,T	Continuity current Current measuring instruments	זרם רציפות מכשירי מדידת זרם	(0 mA to 320 mA]	4%		
262	A	P,T	Insulation resistance Resistance, measuring instruments	התנגדות של בידוד מכשירי מדידת התנגדות	0.01MΩ to 5.00 MΩ	3.2%	MetCal Automated Calibration Software Manufacturer instructions WI-C107	TRANSMILLE 3200 Electrical Test Equipment Calibrator
263	A	P,T			5 MΩ to 2 GΩ	3.6%		
264	A	P,T			2 G Ω to 10 GΩ	5.8%		
265	A	P,T			10 GΩ to 1 TΩ	5.8%		

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Calibration – Electrical Quantities - DC and LF						*כיול – גדלים חשמליים - זרם ישר ותדר נמוך*		
266	A	P,T	Residual current AC Residual Current, Sensing Devices (RCD)	זרם חילופין שיורי מכשירי חישה (RCD)	(Up to 5 Sec.] 3.00 mA to 10.00 mA	2 mA/A	MetCal Automated Calibration Software Manufacturer instructions WI-C107	TRANSMILLE 3200 Electrical Test Equipment Calibrator
267	A	P,T			10.1 mA to 100 mA	1.39 mA/A		
268	A	P,T			101 mA to 1 A	7.81 mA/A		
269	A	P,T			1.01 A to 3 A	34.8 mA/A		
270	A	P,T			(< 190 m Sec.] 3 mA to 10mA	6 mA/A		
271	A	P,T			10.1 mA to 100 mA	6.5 mA/A		
272	A	P,T			101 mA to 1 A	5 mA/A		
273	A	P,T			1.01 A to 3A	5.6 mA/A		
274	A	P,T	Residual current duration AC Loop Resistance Loop Testing Devices.	התנגדות לולאה בזרם חילופין מכשירי בדיקת לולאה	0.05 Ω	0.0075 Ω	Manufacturer instructions WI-C107	
275	A	P,T			0.1 Ω	0.0079 Ω		
276	A	P,T			0.22 Ω	0.0087 Ω		
277	A	P,T			0.33 Ω	0.0097 Ω		
278	A	P,T			0.5 Ω	0.011 Ω		
279	A	P,T						

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Calibration – Electrical Quantities - DC and LF						*כיול – גדלים חשמליים - זרם ישר ותדר נמוך*		
280	A	P,T			1 Ω	0.017 Ω		
281	A	P,T			5 Ω	0.067 Ω		
282	A	P,T			10 Ω	0.13 Ω		
283	A	P,T			100 Ω	1.3 Ω		
					1 k Ω	13 Ω		
284	A	P,T	Auto Loop Resistance AC Auto Loop Resistance. Loop Testing devices.	התנגדות לולאה בזרם AC מכשירי בדיקת לולאה.	1 Ω	0.06Ω	MetCal Automated Calibration Software Manufacturer instructions WI-C107	TRANSMILLE 3200 Electrical Test Equipment Calibrator
285	A	P,T	Earth Bond Resistance Bond Resistance PAT (Portable Appliance Tester)	התנגדות בדיקת חיבור להארקה מכשיריPAT	0.05 Ω	0.0049 Ω		
286	A	P,T			0.1 Ω	0.0053 Ω		
287	A	P,T			0.22 Ω	0.0059 Ω		
288	A	P,T			0.33 Ω	0.0065 Ω		
289	A	P,T			0.5 Ω	0.0076 Ω		
290	A	P,T			1 Ω	0.010 Ω		
291	A	P,T			5 Ω	0.033 Ω		
292	A	P,T			10 Ω	0.062 Ω		
293	A	P,T			100 Ω	0.582 Ω		
294	A	P,T			1 k Ω	5.77 Ω		
295	A	P,T	Earth Bond Current Bond current, PAT (Portable Appliance Tester)	זרם בדיקת חיבור להארקה מכשיריPAT	100.0 mA	9.3 mA		
296	A	P,T			10.00 A	0.24 A		
297	A	P,T			30.00 A	0.59 A		
298	A	P,T	Insulation Resistance	התנגדות בידוד,	0 MΩ	0.0074 MΩ		

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Calibration – Electrical Quantities - DC and LF						*כיול – גדלים חשמליים - זרם ישר ותדר נמוך*		
299	A	P,T	Resistance, PAT (Portable Appliance Tester)	PATמכשירי	0.01 MΩ to 5 MΩ	3 %		
300	A	P,T			5MΩ to 2 GΩ	3.5 %		
301	A	P,T	Leakage Current, PAT (Portable Appliance Tester)	זליגת זרם להארקה PATמכשירי	2.000 mA	0.038 mA	MetCal Automated Calibration Software Manufacturer instructions WI-C107 WI-C100	TRANSMILLE 3200 Electrical Test Equipment Calibrator
302	A	P,T			4.700 mA	0.084 mA		
303	A	P,T			7.700 mA	0.136 mA		
			Flash Voltage PAT (Portable Appliance Tester)	מתח פריצת בידוד PATמכשירי	Class 1 (1.5 kV) (1 kV to 1.8 kV]			
304	A	P,T			1000 V	57 V		
305	A	P,T			1500 V	81 V		
					Class 2 (3 kV) (2 kV to 3 kV]			
306	A	P,T			3000 V	151 V		
			Flash Current PAT (Portable Appliance Tester)	זרם פריצת בידוד PAT מכשירי	(1 mA to 3 mA]			
307	A	P,T			1.00 mA	0.06 mA		
308	A	P,T	Line Voltage Measurement of line voltage	מתח רשת חשמל, מדידת מתח רשת חשמל	(200 V (rms)) to 260 V(rms)]	1.2 %		
			Breakdown/Hipot Measurement of high voltage	מדידת מתח גבוה	(3 kV AC @ 50 Hz)		Manufacturer instructions WI-C107	
309	A	P,T			1.00 kV	0.05 kV		
310	A	P,T			2.00 kV	0.06 kV		
311	A	P,T			3.00 kV	0.06 kV		
					(12 kV AC @ 50 Hz)			
312	A	P,T						

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Calibration – Electrical Quantities - DC and LF								*כיול – גדלים חשמליים - זרם ישר ותדר נמוך*
313	A	P,T			4.00 kV	0.07 kV		
314	A	P,T			6.00 kV	0.08 kV		
315	A	P,T			8.00 kV	0.10 kV		
316	A	P,T			10.00 kV	0.11 kV		
					(25 kV AC @ 50 Hz)			
317	A	P,T			12 kV to 25 kV	1.2% O.R.		
					3 kV DC			
318	A	P,T			1.00 kV	0.05 kV		
319	A	P,T			2.00 kV	0.06 kV		
320	A	P,T			3.00 kV	0.06 kV		
					(12 kV DC)		Manufacturer instructions WI-C107	HV Probe 80K-40 DMM TRANSMILLE 3200
321	A	P,T			4.00 kV	0.07 kV		
322	A	P,T			6.00 kV	0.08 kV		
323	A	P,T			8.00 kV	0.09 kV		
324	A	P,T			10.00 kV	0.10 kV		
325	A	P,T			12.00 kV	0.12 kV		
					(40 kV DC)			
326	A	P,T			12 kV to 40 kV	1.0% O.R.		

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Calibration – Electrical Quantities - DC and LF						***כיול – גדלים חשמליים - זרם ישר ותדר נמוך***		
			Measurement of current at high voltage	מדידת זרם במתח גבוה	1 kV AC @ 50 Hz		Manufacturer instructions WI-C107	
327	A	P,T			200 µA	1.7 µA		
328	A	P,T			2.00 mA	0.04 mA		
329	A	P,T			20.00 mA	0.16 mA		
330	A	P,T			1 kV DC			
331	A	P,T			200 µA	1.7 µA		
332	A	P,T			2.00 mA	0.04 mA		
333	A	P,T			20.00 mA	0.16 mA		
			DC High Voltage, Source	מחוללי מתח גבוה ישר	40 kV DC)		Manufacturer instructions WI-C107	SPELLMAN SL40P2000 HV Probe 80K-40 DMM
334	A	P,T			1 kV to 40 kV	2.4% O.R.		

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Calibration – Electrical Quantities - RF Frequency, Time						***כיול – גדלים חשמליים - תדר גבוה, זמן***		
335	A	P	Frequency, Sources	תדר, מחוללי תדר	[0.037 Hz to 10 MHz]	10^{-11} (24 h)	MetCal WI-C102 WI-C105 WI-C106	FLUKE 910R Wavetek 9500 H.P.5248 M H.P. 53132 A Via GPS System With Ref. Locked to 910R
336	A	P			[10 MHz to 3.2 GHz]	5×10^{-9} (0.3 h)	MetCal WI-C102 WI-C105 WI-C106	FLUKE 910R Wavetek 9500 H.P.5248 M H.P. 53132 A Via GPS System With Ref. Locked to 910R (with 9500 + 9530)
337	A	T			[10 MHz to 3.2 GHz]	4.8×10^{-5} (0.3 h)	MetCal WI-C102 WI-C105 WI-C106	Wavetek 9500 H.P.5248 M H.P. 53132 A With Internal Reference
338	A	P	Frequency. Counters	תדר, מוני תדר	[0.1 Hz to 100 MHz]	4.8×10^{-9} (0.3 h)	WI-C102 WI-C105 WI-C106	With Ref. Locked to 910R
339	A	P			[100 MHz to 3 GHz]	4.8×10^{-10} (0.3 h)		With Ref. Locked to 910R (with 9500 + 9530)
340	A	T			[0.1 Hz to 3 GHz]	1.4×10^{-5} (0.3 h)		With Internal Reference
341	A	P;T	Timers, stopwatches	שעוני עצר, מוני זמן	[1 sec to 24 hr]	0.1 sec	Manufacturer instructions WI-C070	השוואה למדיד אב

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Calibration – Electrical Quantities - RF Frequency, Time						***כיול – גדלים חשמליים - תדר גבוה, זמן***		
342	A	P;T	Oscilloscope Time markers function: Square wave, Pulse, Narrow Triangle	ציר אופקי במשקף תנודות	[0.45 ns to 55 sec]	0.038 µs/s	Software MetCal Software WI-C102	Wavetek 9500 Fluke 910R External reference input in the range 1 MHz to 20 MHz
343	A	P;T	Oscilloscope Amplitude Square Wave	ציר אנכי במשקף תנודות	Input impedance 1 MΩ Peak to peak amplitude (40 µV to 1 mV]	10 mV/V + 10 µV	MetCal Software WI-C102 WI-C105 WI-C106	Wavetek 9500 Fluke 910R External reference input in the range 1 MHz to 20 MHz
344	A	P;T			(1 mV to 200 V]	1 mV/V + 10 µV		
345	A	P;T	Oscilloscope Amplitude Square Wave	ציר אנכי במשקף תנודות	Input impedance 50 Ω Peak to peak amplitude (40 µV to 1 mV pk-pk]	10 mV/V + 10 µV	MetCal Software WI-C102 WI-C105 WI-C106	Wavetek 9500
346	A	P;T			(1 mV to 5 V pk-pk]	1 mV/V + 10 µV		
347	A	P;T	Oscilloscope Rise Time	זמן עלית האות של משקף תנודות	Rise time, From 150 ps]	14 ps	MetCal Software WI-C102 WI-C105 WI-C106	Wavetek 9500
348	A	P;T	Oscilloscope Bandwidth:	רוחב סרט של משקף תנודות	[0.1 Hz to 300 MHz]	0.23 db	MetCal Software WI-C102 WI-C105 WI-C106	Wavetek 9500
349	A	P;T			[300 MHz to 550 MHz]	0.23 db		
350	A	P;T			[550 MHz to 1.1GHz]	0.29 db		

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Calibration – Electrical Quantities - RF Frequency, Time						*כיול – גדלים חשמליים - תדר גבוה, זמן*		
351	A	P;T			[1.1 GHz to 3.2 GHz]	0.36 db		
352	A	P;T	Oscilloscope Flatness	מישוריות האות כתלות בתדר ביחס לתדר הייחוס	[0.1 Hz to 300 MHz]	2.3 %	MetCal Software WI-C102 WI-C105 WI-C106	Wavetek 9500 Leveled Sine Wave Amplitude 50 kHz Ref
353	A	P;T			[300 MHz to 550 MHz]	3.8 %		
354	A	P;T			[550 MHz to 1.1 GHz]	4.9 %		
355	A	P;T			[1.1 GHz to 3.2 GHz]	6.0 %		
356	A	P;T	Oscilloscope Input Capacitance	קיבול כניסה של משקף תנודות	[1 pF to 65 pF]	7 mF/F	MetCal Software WI-C102 WI-C100	Wavetek 9500 Input impedance 50 Ω

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Calibration – Mechanical Quantities - Form, Angle						***כיול – גדלים מכניים - צורה, זווית***		
357	A	P	Flank Angle Screw Plug Gauges (parallel) including check and setting Plug	זווית השן מדיד הברגה זכר מקביל	Plug Diameter [1 mm to 305 mm]	[2+(800/M×P)] Minutes of arc	WI-C020	**M** is projector magnification and *P* is pitch in mm
358	A	P	Flank angle Screw Plug Gauges (taper)	זווית השן מדיד הברגה זכר קוני	Plug Diameter [1 mm to 305 mm]	[2+(800/M×P)] Minutes of arc	WI-C020	*M* is projector magnification and *P* is pitch in mm
359	A	P	Flatness of Optical Flats in diameter of 10 mm – 50 mm	מישוריות של משטחים אופטיים בעלי קוטר 10 – 50 mm	Above 0.05 µm	0.1 µm	FED-GG-0-635 JIS B 7430 JIS B 7431	Optical flat/parallel מערכת כיול מקבילונים ועדשה מישורית The uncertainty quoted is for the departure from flatness of parallelism, i.e. the distance separating the two parallel planes, which just enclose by
360	A	P	Parallelism of Optical Parallels in diameter of 10 mm – 50 mm	מקבילות של משטחים אופטיים בעלי קוטר 10 – 50 mm	Above 0.01 µm	0.1 µm	WI-C009	The uncertainty quoted is for the departure from flatness of parallelism, i.e. the distance separating the two parallel planes, which just enclose by

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Calibration – Mechanical Quantities - Form, Angle								*כיול – גדלים מכניים - צורה, זווית*
361	A	P;T	Flatness of Granites or Cast iron surfaces in Grade 00	מישורית של לוחות משטח גרניט וברזל יציקה ברמה 00	Above 0.1 µm	[1.5+0.8* length] µm	DIN 876 P1,2 ISO 8152 P1,2 GGG-P-463-C	עד $0.09\ m^2$ נבדק באמצעות גשש אורך. מעל $0.09\ m^2$ נבדק במערכת פלסים אלקטרוניים. The uncertainty quoted is for the departure from flatness, straightness, parallelism, or squareness i.e. the distance separating the two parallel planes which, just enclose the surface under consideration (Length in m)
362	A	P	Straightness, flatness and parallelism of Granite, Cast iron and Steel straightedges in Grade 00	ישרות, מישוריות, מקבילות של סרגל ישרות מתכת או גרניט ברמה 00	Above 1 µm	4.3 µm	DIN 874 P.1	גששי אורך
363	A	P	Straightness Knife edge, straight edge	סרגל שערה	Up to 500 mm]	1.5 µm	DIN 874 P.2	מקור אור מונוכרומטי, גששי אורך
364	A	P	Flatness, Parallels	מקבילים	Up to 50*100*400]	2 µm	DIN 6346 DIN 7151 DIN 7168	גששי אורך
365	A	P	Parallelism, Parallels	מקבילים	Up to 50*100*400]	2 µm	DIN 6346 DIN 7151 DIN 7168	גששי אורך
366	A	P	Perpendicularity,	ניצבות,	Up to 300 mm]	3.0 µm	DIN-875	גששי אורך

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Calibration – Mechanical Quantities - Form, Angle								*כיול – גדלים מכניים - צורה, זווית*
367	A	P	Square, blade type	זוויתנים	(300 mm to 600 mm]	5 µm	JIS B 7526	מד ניצבות
368	A	P			(600 mm to 900 mm]	8 µm		
369	A	P	Parallelism Square, blade type	מקבילות זוויתנים	Up to 300 mm]	3 µm	DIN-875 JIS B 7526	גששי אורך
370	A	P			(300 mm to 600 mm]	5 µm		
371	A	P			(600 mm to 900 mm]	8 µm		
372	A	P	Flatness, Square, blade type	מישוריות זוויתנים	Up to 300 mm]	3 µm		
373	A	P			(300 mm to 600 mm]	5 µm		
374	A	P			(600 mm to 900 mm]	8 µm		
375	A	P	Perpendicularity, Cylinder	גליל ניצבות	Up to 600 mm]	2 µm	JIS B 7539	
376	A	P	Perpendicularity, Universal Box Angles	ניצבות אביזר דפינה אוניברסאלי	Up to 100 mm]	3 µm	DIN 875 DIN 876	
377	A	P			(100 mm to 300 mm]	5 µm		
378	A	P			(300 mm to 600 mm]	8 µm		
379	A	P	Flatness, Universal Box Angles	מישוריות אביזר דפינה אוניברסאלי	Up to 100 mm]	3 µm	DIN 875 DIN 876	
380	A	P			(100 mm to 300 mm]	5 µm		
381	A	P			(300 mm to 600 mm]	8 µm		
382	A	P	Parallelism	מקבילות	Up to 100 mm]	3 µm	DIN 875	

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Calibration – Mechanical Quantities - Form, Angle						***כיול – גדלים מכניים - צורה, זווית***		
383	A	P	Universal Box Angles	אביזר דפינה אוניברסאלי	(100 mm to 300 mm]	5 µm	DIN 876	
384	A	P			(300 mm to 600 mm]	8 µm		
385	A	P	Squareness Right angle and box angle plate	ברך, קוביה	Up to 600 mm]	[3 + 1 per 100 mm] µm	WI-C050	מד ניצבות
386	A	P	Parallelism Right angle and box angle plate	ברך, קוביה	Up to 600 mm]	[1 + (1 per 100 mm)] µm	WI-C050	מד ניצבות
387	A	P	Perpendicularity Square master	מד ניצבות	600 mm	2.1 µm	נתוני יצרן WI-C018	השוואה למדיד אב לניצבות
388	A	P	Perpendicularity Vee blocks	פריזמות	Up to 150 mm]	2.1 µm	BS 3731 JIS B 7540	Grade 00 גששי אורך גליליים
389	A	P	Flatness, Vee blocks	פריזמות	Up to 150 mm]	2.1 µm	BS 3731 JIS B 7540	Grade 00 גששי אורך גליליים
390	A	P	Parallelism Vee blocks	פריזמות	Up to 150 mm]	2.1 µm	BS 3731 JIS B 7540	Grade 00 גששי אורך גליליים
391	A	P	Angle Sines bars and tables	זווית סרגלים ושולחנות סינוס	Up to 500 mm]	2 "	BS 3064 GGG-B 121b DIN 2273	Angle is estimated by measuring distance מקבילונים בלוק זוויתי
392	A	P	Angle Level	פלס	± 5 º	0.5 "	DIN 887 BS 958	1 µ/m sensitivity מייצר זוויות קטנות
393	A	P	Angle Clinometer	קלינומטר	Up to 90 ^{0}]	10 "	DIN 887 BS 958	מייצר זוויות קטנות

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Calibration – Mechanical Quantities - Form, Angle						***כיול – גדלים מכניים - צורה, זווית***		
394	A	P	Angle Bevel protractor	מד זווית מתכוונן	up to 360 º)	3´	BS 1685	בלוק זוויתי גששי אורך מד ניצבות
395	A	P;T	Rotational Speed Mechanical tachometer	מהירות סיבוב (סל״ד) מד סל״ד מכני	[1 to 5000] RPM	0.1 % OR or 0.2 RPM Whichever is greater	Manufacturer instructions WI-C069	Counter מונה
396	A	P;T	Rotational Speed Optical tachometer	מהירות סיבוב (סל״ד) מד סל״ד אופטי	[1 to 2500] RPM	0.02 % OR or 1 resolution Whichever is greater		Function generator מחולל אותות
397	A	P;T	Rotational Speed Optical tachometer	מהירות סיבוב (סל״ד) מד סל״ד אופטי	[2500 to 99999] RPM	0.005 % OR		Function generator מחולל אותות

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Calibration – Mechanical Quantities - Hardness Meters						***כיול – גדלים מכניים - מדי קושיות***		
398	A	P;T	Rockwell hardness testing machine	מכשירים למדידת קשיות בשיטת רוקוול	HRA [20 to 95]	0.45 HRA	ASTM E18 ISO 6508-2	Indirect verification השוואה לחומר יחוס סטנדרטי
399	A	P;T			HRBW [10 to 100]	0.7 HRBW		
400	A	P;T			HRC [10 to 70]	0.45 HRC		
401	A	P;T			HREW [70 to 100]	0.9 HREW		
402	A	P;T			HR15N [70 to 94]	0.5 HR15N		
403	A	P;T			HR30N [42 to 86]	0.5 HR30N		
404	A	P;T			HR45N [20 to 77]	0.5 HR45N		
405	A	P;T			HR15TW [67 to 93]	0.7 HR15TW		
406	A	P;T			HR30TW [29 to 82]	0.7 HR30TW		
407	A	P;T			HR45TW [10 to 72]	1.1 HR45TW		
408	A	P;T	Brinell hardness testing machine	מכשירים למדידת קשיות בשיטת ברינל	HBW 2.5 / 187.5	2% HBW	ASTM E10	Indirect verification השוואה לחומר יחוס סטנדרטי
409	A	P;T	Vickers hardness testing machine	מכשירים למדידת קשיות בשיטת וויקרס	(0.1 to 0.5) HV	1.5% HV	ASTM E384 ISO 6507-2	Indirect verification השוואה לחומר יחוס סטנדרטי
410	A	P;T			(1 to 100) HV	1.2% HV		

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Calibration – Mechanical Quantities - Hardness Meters						***כיול – גדלים מכניים - מדי קושיות***		
			Shore hardness testing equipment (durometer)	מכשירים למדידת קשיות בשיטת שור	Type A Instruments		ASTM D2240 ISO 21509 ISO 18898	Direct verification כיול כח קפיץ ביחידות Shore Durocalibrator בדיקת פרמטרים של החודרן Profile projector Microscope Indenters with parameters out of the nominal range may be calibrated at stated uncertainties as well
411	A	P	SHORE A	שור A	[0 to 100] Shore	0.4 SHORE A		
412	A	P	Indenter extension	אורך החודרן	[0.1 to 2.54] mm	0.010 mm		
413	A	P	Indenter diameter	קוטר חוד החודרן	[0.76 to 0.82] mm	0.008 mm		
414	A	P	Indenter angle	זווית החודרן	[34.75° to 35.25°]	0.05°		
415	A	P	Intender diameter	קוטר החודרן	[1.1 to 1.4] mm	0.03 mm		
416	A	P	Presser foot hole diameter	קוטר קדח הבסיס	[2.5 to 3.5] mm	0.03 mm		
417	A	P	Presser foot diameter	קוטר בסיס לחיצה	[10 to 50] mm	0.05 mm		
					Type D Instruments			
418	A	P	SHORE D	שור D	[10 to 100] Shore	0.4 SHORE D		
419	A	P	Indenter extension	אורך החודרן	[0.1 to 2.54] mm	0.010 mm		
420	A	P	Indenter radius	רדיוס חוד החודרן	[0.088 to 0.112] mm	0.008 mm		
421	A	P	Indenter angle	זווית החודרן	[29° to 31°]	0.05°		
422	A	P	Intender diameter	קוטר החודרן	[1.1 to 1.4] mm	0.03 mm		
423	A	P	Presser foot hole diameter	קוטר קדח הבסיס	[2.5 to 3.5] mm	0.03 mm		
424	A	P	Presser foot diameter	קוטר בסיס לחיצה	[10 to 50] mm	0.05 mm		

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Calibration – Mechanical Quantities - Length									***כיול – גדלים מכניים - אורך***
425	A	P	Gauge Blocks Comparator	מערכת כיול מקבילונים	Up to 100 mm	0.05µm		Euramet cg-2	Gauge blocks
426	A	P	Length, Gauge Blocks (by Comparison)	אורך, מקבילונים		Class (see note) **C**	 **D**	DIN 861 ISO 3650 BS 4311 NF E11-010 OIML No. 30 BS 888	קומפרטור מקבילונים **Class C** uncertainties apply to the measurement of length of steel gauges by comparison with grade K standards of length of a similar material. Class C uncertainties apply to new grade 0, 1 and 2 gauges to the aforementioned standard and represent the best capability for all grades of used gauges to the aforementioned standard. **Class D** Class D uncertainties represent the best capability for the measurement of length of tungsten carbide and ceramic gauges by comparison with grade K standards of length of a dissimilar material
427	A	P			Up to 10 mm}	0.08 µm	0.10 µm		
428	A	P			(10 mm to 25 mm]	0.10 µm	0.13 µm		
429	A	P			Sizes: 30, 40, 50	0.12 µm	0.17 µm		
430	A	P			Sizes : 60, 70, 75	0.15 µm	0.21 µm		
431	A	P			Sizes : 80, 90, 100	0.18 µm	0.25 µm		
432	A	P			Up to 0.4 in}	3 µin	4 µin		
433	A	P			(0.4 to 1 in]	4 µin	5 µin		
434	A	P			2 in	5 µin	7 µin		
435	A	P			3 in	6 µin	8 µin		
436	A	P			4 in	7 µin	10 µin		
437	A	P	Length Gauge Block accessories	אורך, אביזרים מקבילונים	160 mm	2 µm		DIN 861 P-2	מכונת מדידה SIP / TRIMOS 305M
438	A	P	Length, Length Bars	אורך, מוטות אורך מדיד	Up to 775 mm]	[0.1 + 2×length] µm		BS 5317 ISO 3650 DIN 861	Length bar Length in m

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Calibration – Mechanical Quantities - Length								***כיול – גדלים מכניים - אורך***
439	A	P	Length, Length Gauges	אורך, מדידי אורך	Up to 1000 mm]	[0.1 + 2.5×length] µm	ISO 3650 DIN 861 ASME B89.1.13	Length bar Length in m
440	A	P	Length, Step Gauge	אורך, מקבילונים מדורגים	Up to 600 mm]	[0.1 + 2.5×length in m] µm	נתוני יצרן WI-C019	Length bar Length in m
441	A	P	Length Measuring Machine	מכונת מדידת אורך	Up to 500 mm	[0.1 + 2.5×length] µm	Manufacturer Instructions WI-C002 WI-C076	Length bar Length in m
442 443	A A	P P	Length, Plain Plug Gauges	אורך, מדידי תקע חלק	[1 to 25.4] mm (25 mm to 100] mm	1 µm 1.5 µm	ISO R/286 DIN 7162 DIN 7163 DIN 7164 H28/SEC.6 DIN 2269	מכונת מדידה SIP / TRIMOS 305M מיקרומטר שולחני
444 445 446	A A A	P P P	Diameter Plain Rings	טבעות חלקות	[2 mm to 100 mm] (100 mm to 150 mm] (150 mm to 205 mm]	0.4 µm 1.5 µm 2 µm	DIN 2250	מכונת מדידה SIP / TRIMOS 305M by comparison to gauge block in clamp calibration by comparison to standard plain ring provides lower uncertainties
447	A	P	Diameter Thread Measuring Cylinders	תיילים לבדיקת מדיד הברגה	[0.1 mm to 6 mm]	0.7 µm	H28/SEC.22A	מכונת מדידה SIP / TRIMOS 305M

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Calibration – Mechanical Quantities - Length						***כיול – גדלים מכניים - אורך***		
448	A	P	Pitch Diameter Screw Plug Gauges (parallel) including check and setting Plug	מדיד הברגה זכר – מקביל	Plug Diameter [1 mm to 100 mm]	3 µm	F-STD-H-28 ISO 228/1-2 ISO 1502 ISO 2903/4 ISO 7/1,29 BS 919/1,2,3 BS 849 BS 3409/1,2 BS 4377/2 BS 21 DIN 103/9 DIN 405 DIN 2999/4 B.N.A.e HELI-COIL WI-C020 WI-C023 WI-C024	כיול זווית השן מדיד הברגה זכר קוני – ראה בטכנולוגיה כיול – גדלים מכניים – צורה, זווית
449	A	P			(100 mm to 305 mm)	5 µm		
450	A	P	Pitch Screw Plug Gauges (parallel) including check and setting Plug	פסיעת התבריג מדיד הברגה זכר מקביל	Plug Diameter [1 mm to 305 mm]	1.5 µm		
451	A	P	Pitch Diameter Screw Plug Gauges (taper)	מדיד הברגה זכר - קוני	Plug Diameter [1 mm to 100 mm]	3 µm		כיול זווית השן מדיד הברגה זכר קוני – ראה בטכנולוגיה כיול – גדלים מכניים – צורה, זווית
452	A	P			(100 mm to 305 mm]	5 µm		
453	A	P	Pitch Screw Plug Gauges (taper)	פסיעת התבריג מדיד הברגה זכר קוני	Plug Diameter [1 mm to 305 mm]	1.5 µm		
454	A	P	Pitch Diameter Thread rings (parallel)	טבעות הברגה – מקבילה	Ring diameter [1.2 mm to 3 mm]	Not relevant	F-STD-H 28 ISO 228/1-2 ISO 1502	Go no go test by means of check plug מכונת מדידה
455	A	P			(3 mm to 100 mm]	4 µm		

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Calibration – Mechanical Quantities - Length								***כיול – גדלים מכניים - אורך***
456	A	P			(100 mm to 305 mm]	5 µm	ISO 2903/2904 BS 919/1,23 BS 84 DIN 103/9 DIN 405 DIN 2999/2 B.N.A.e	SIP / TRIMOS 305M
457	A	P	Micrometer External	מיקרומטר חיצוני	Up to 2000 mm]	Heads 2.0 µm Setting and extension rods: [1 + 5×length in m] µm	ISO 3611 DIN 863 ASME B89.1.13 JIS B 7502	מקבילונים מוטות אורך
458	A	T			Up to 600 mm]	Heads 3.0 µm Setting and extension rods: [1 + 5×length in m] µm		
459	A	P	Micrometer Internal	מיקרומטר פנים	Up to 300 mm] extension rod to 1000 mm]	Heads 2.0 µm Setting and extension rods [1 + 5×length in m] µm	DIN 863 ASME B89.1.13	טבעות חלקות מכונת מדידה
460	A	P;T	Micrometer Depth	מיקרומטר עומק	Up to 250 mm]	Heads 2.0 µm Setting and extension rods [1 + 5×length in m] µm	DIN 863 ASME B89.1.13	מקבילונים
461	A	P	Micrometers (indicating digital and electronic)	מיקרומטר (כולל דיגיטלי)	Up to 2000 mm]	[1 + 5×length in m] µm Minimum 1.5 µm	ISO 3611 DIN 863 ASME B89.1.13 JIS B 7502	מקבילונים מוטות אורך
462	A	T			Up to 600 mm]	[1 + 5×length in m] µm Minimum 3.0 µm		
463	A	P	Three point Internal and bore micrometer	מיקרומטר פנים תלת נקודתי	[2 mm to 50 mm]	2 µm	DIN 863 Manufacturer Instructions WI-C012	טבעות חלקות
464	A	P			(50 mm to 150 mm]	5 µm		

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Calibration – Mechanical Quantities - Length								*כיול – גדלים מכניים - אורך*
465	A	P	Micrometer head	ראש מיקרומטר	Up to 50 mm]	2 µm	Manufacturer;s instructions WI-C006	
466	A	P	Height setting micrometer	מד גובה מיקרומטרי	Up to 300 mm]	Heads 1.0 µm between any two points. Stepped column 2.5 µm Overall performance 3.0 µm	ISO 7863	מקבילונים, מוטות אורך
467	A	P	Riser Block	בסיס הגבהה למד גובה מיקרומטרי	Up to 150 mm]	2.5 µm	WI-C005	
468	A	P			(150 to 300 mm]	5 µm		
469	A	P;T	Vernier Caliper, depth Gauges	זחון ורנייר	Up to 2000 mm]	Overall performance [10 + 30× length in m] µm	DIN EN ISO 13385-1 DIN EN ISO 13385-2 DIN 862 -1988	מקבילונים, מוטות אורך, בודק זחונים
470	A	P;T	Caliper (digital and electronic)	זחון אלקטרוני ודיגיטלי	Up to 2000 mm]	Overall performance [10 + 30× length in m] µm	DIN EN ISO 13385-1 DIN EN ISO 13385-2 DIN 862 -1988	מקבילונים, מוטות אורך, בודק זחונים
471	A	P	Micrometer Heads Dial testers	מערכת כיול חוגנים	Up to 25 mm	0.2 µm	WI-C028	Gauge blocks
472	A	P;T	Height Gauge Electronic microprocessor Controlled height Gauge	מד גובה	Up to 1000 mm]	[1 + 5× length in m] µm	BS 1643 JIS B 7517	
473	A	P;T	Dial Indicator	חוגן	Up to 3 mm]	0.3 µm	DIN 878 DIN 879 JIS B 7509	בודק חוגנים מכונת מדידה
474	A	P;T	Length gauge	גשש אורך	[3-60] mm	1 µm		

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Calibration – Mechanical Quantities - Length								*כיול – גדלים מכניים - אורך*
475	A	P;T			[60-100] mm	1.5 µm	ANSI B89.1.10M NF E 11-056 ISO 13102	
476	A	P;T	Lever type dial indicator Lever type gauge	חוגן מנופי גשש מנופי	Up to 3 mm]	0.3 µm	BS 2795 PT.1 DIN 2270 MIL-I-18422D JIS B 7533 ISO 13102	בודק חוגנים
477	A	P;T	Thickness gauge	מד עובי	Up to 50 mm	2 µm	Manufacturer Instructions WI-C037	מקבילוני אורך Gauge blocks
478	A	P;T	Dial caliper gage (external type)	מד עובי זרועות	Up to 150 mm	10 µm	Manufacturer Instructions WI-C037	מקבילוני אורך Gauge blocks
479	A	P;T	Dial caliper gage (internal type)	מד חריצים	Up to 125 mm	10 µm	Manufacturer Instructions WI-C035	מיקרומטר, מקבילוני אורך Micrometer, Gauge blocks
480	A	P	Feeler Gauge	מד מרווח עלים	Up to 1 mm]	4 µm	DIN 2275	מיקרומטר
481	A	P;T	Measuring microscope	מיקרוסקופ מדידה	Up to 300 mm	[2 + (25/M)] µm	נתוני יצרן WI-C034	סרגל אופטי M is total magnification
482	A	P;T	Profile projectors	מטול פרופילים	Up to 300 mm	[2 + (25/M)] µm	נתוני יצרן WI-C034	סרגל אופטי M is total magnification
483	A	P	Bore comparators (bore gauge)	מד קדח גשר	[6 mm to 150 mm]	2 µm	JIS B 7515 MIL-G-26762A MIL-G-26762A	בודק חוגנים טבעות חלקות מיקרומטר

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Calibration – Mechanical Quantities - Length						***כיול – גדלים מכניים - אורך***		
484	A	P	Bore comparators Cylinder gauge	פין מפציל	[1 mm to 18 mm]	2 µm	נתוני יצרן WI-C011	
485 486	A	P	Optical scale	סרגל אופטי	Up to 1 mm 1 mm – 300 mm	0.5 µm 1 µm	JIS B 7541 Manufacturer Instructions WI-C039	מכונת מדידה TRIMOS/ SIP 305M
487 488	A A	P P	Measuring rule	סרגל מדידה	Up to 500] mm (500 to 2000] mm	20 µm 50 µm	DIN 866, JIS-B 7516 Manufacturer Instructions WI-C078	מיקרוסקופ מדידה כייל סרגלי וסרטי מדידה Measuring microscope Scale and Tape Calibration Unit.
489 490	A	P	Measuring tape	סרט מדידה	Up to 10] m (10 to 50] m	0.10 mm 0.40 mm	OIML-R-35 Manufacturer Instructions WI-C078	כייל סרגלי וסרטי מדידה Scale and Tape Calibration Unit.
491	A	P;T	Length Length meter	אורך מד אורך	[1 to 1000] m	0.01 m or 0.2 % OR Whichever is greater	WI-C069	Mechanical tachometer (Mode “m”) מונה מטרים
492	A	P;T	Surface Speed Surface Speed meter	מהירות פני השטח מד מהירות פני השטח	[2 to 500] m/min	0.1 m/min or 0.2 % or Whichever is greater	WI-C069	Mechanical tachometer (Mode “m/min”) מד מהירות
 493 494 495	 A A	 P P P	Test sieves	נפות	Nominal aperture size : Up to 0.2 mm 0.2 mm – 1 mm 1 mm – 5 mm	 0.003 mm 0.005 mm 0.010 mm	ASTM E11 ISO 3310 BS 410	מטול פרופילים, זחון Profile projector, caliper.

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Calibration – Mechanical Quantities - Length						*כיול – גדלים מכניים - אורך*		
496	A	P			5 mm – 15 mm	0.020 mm		
497	A	P			15 mm – 30 mm	0.050 mm		
498	A	P			Above 30 mm	0.10 mm		
499	A	P:T	Extensometer	מד התארכות	[0.01 mm to 50 mm]	0.004 mm	ASTM E83 ISO 9513 ISO 5893	Extensometer calibrator
500	A	P:T	Extensometer (displacement)	מד התארכות	[0.01 mm to 1000 mm]	0.006 mm	Manufacturer Instructions WI-C075	High precision dial gauge, Length gauge
501	A	P;T	Length measurements	מדידת אורך	Up to 125 mm]	0.003 mm	Customer requirements WI-C081	
502	A	P;T			(125 mm to 200 mm]	0.005 mm		
503	A	P;T			(200 mm to 600 mm]	0.007 mm		
504	A	P;T			(600 mm to 2000 mm]	0.05 mm		

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Calibration – Physical Quantities - Optics						*כיול – גדלים פיזיקליים - אופטיקה*		
505	A	P,T	Optical emitting devices and Meters	מכשיר פולט קרינה אופטית ומד קרינה אופטית	Power הספק 3 n.W to 3 m.w at 270 to 950 nm and 15µW to 150 W at 193 nm to 10600 nm	3.5% of Reading	In house procedure Based on: IEC 60825 ISO 13694 WI-C203	
506	A	P,T	Light emitting devices and Meters	מכשיר פולט אור ומד קרינה אופטית	Energy 20µJ to 4 KJ at 193 to 10600 nm	5% of Reading	In house procedure Based on: IEC 60825 ISO 13694 WI-C203	
507	A	P,T	Optical emitting devices and Meters	מכשיר פולט קרינה אופטית ומד קרינה אופטית	Frequency & Time תדר וזמן Up to 0.7 MHz Min. Rise/Fall Time 2 nsec	1 nsec	In house procedure Based on: IEC 60825 ISO 13694 WI-C202	
508	A	P,T	Light Meters	מד קרינה אופטית	Wavelength 25 nm to 3507 nm	2x10-4 nm	In house procedure Based on: IEC 60825 ISO 13694 WI-C200	NIST Atomic Spectra Database
509	A	P,T	Optical emitting devices and Meters	מכשיר פולט קרינה אופטית ומד קרינה	Wavelength אורך גל 200 nm to 1100 nm	1 nm	In house procedure Based on: IEC 60825 ISO 13694 WI-C200	
510	A	P,T	Light emitting devices and Meters	מכשיר פולט אור ומד אור	Light אור 0 to 2.0E+5 lux	0.5 res or 5.0 % Whichever is greater	In house procedure The CIE 1924 photopic V(λ) luminosity function WI-C201	
511	A	P,T	Light emitting devices and Meters	מכשיר פולט אור ומד אור	Visible light 6.85*10-3 cd/m2 to 3120 kcd/m2	5% of Reading		Calibration can be given in other units as required.

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Calibration – Physical Quantities - Force, Torque						***כיול – גדלים פיזיקליים - כח, מומנט***		
512	A	P,T	Force calibration in tension, force measurement machine	כיול כח במתיחה, מכונות למדידת כח	[0.1 kN to 100 kN]	1.5 N/kN of verification force	ISO 7500-1 ASTM E4 Manufacturer instructions WI-C056	Force load cell מתמר כח Calibration can be given in other units as required. 1 N/kN = 0.1%
513	A	T	Force calibration in tension, material testing machine	כיול כח במתיחה, מכונות למדידת כח	[0.1 kN to 500 kN]	2.0 N/kN of verification force		
514	A	P;T	Force calibration in compression, material testing machine	כיול כח בלחיצה, מכונות למדידת כח	[0.1 kN to 1 MN]	2.0 N/kN of verification force		כולל כיול מכונות בדיקה לפי דרישות תקן ישראלי 26 חלק 4.1
515	A	P;T			(1 MN to 2.3 MN]	2.4 N/kN of verification force		
516	A	P;T	Force calibration in tension and compression, push pull force measurement machine	כיול כח בלחיצה ומתיחה מכונות למדידת כוח	(0.005 N to 1.2 kN]	1.0 N/kN of verification force		משקולות
517	A	P	Force calibration in tension and compression, Proving devices	כיול כח בלחיצה ומתיחה תאי (טבעות) כוח	[0.005 N to 1.2 kN]	0.5 N/kN of verification force	ISO 376 Euramet cg-4	משקולות , מתמר כח
518	A	P			[1 kN to 20 kN]	0.7 N/kN of verification force		
519	A	P	Force calibration in compression, Proving devices	כיול כח בלחיצה תאי (טבעות) כוח	[20 kN to 1 MN]	1.0 N/kN of verification force		
520	A	P			[1 MN to 2.3 MN]	2.0 N/kN of verification force		
521	A	P	Force calibration in tension, Proving devices	כיול כח במתיחה תאי (טבעות) כוח	[20 kN to 100 kN]	1.0 N/kN of verification force		

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Calibration – Physical Quantities - Force, Torque						*כיול – גדלים פיזיקליים - כח, מומנט*		
522	A	P	Torque Torque wrenches and drivers	מומנט ידית מומנט, מברגת מומנט	[0.01 Nm to 1000 Nm]	0.5 % OR	ISO 6789	מתמרי מומנט Calibration can be given in other units as required OR – Of Reading
523	A	P						
524	A	P	Torque Mechanical and Electronic torque calibration equipment	מומנט מכשירים למדידת מומנט (מכאניים ואלקטרוניים)	[0.001 Nm to 0.01 Nm]	0.25 % OR	BS 7882 Euramet cg-14 Manufacturer's instructions WI-C061	OR – Of Reading קורות כיול ומשקולות
525	A	P			[0.01 Nm to 1000 Nm]	0.1 % OR		
526	A	T	Torque Mechanical and Electronic torque calibration equipment	מומנט מכשירים למדידת מומנט (מכאניים ואלקטרוניים)	[0.1 Nm to 50 Nm]	0.2 % OR		קורות כיול ומשקולות
527	A	T	Torque Mechanical and Electronic torque calibration equipment	מומנט מכשירים למדידת מומנט (מכאניים ואלקטרוניים)	(50 Nm to 1000 Nm]	1 % OR		מתמרי מומנט OR – Of Reading

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Calibration – Physical Quantities - Humidity						*כיול – גדלים פיזיקליים - לחות*		
			Relative humidity RH meters RH data loggers RH probes RH transducers לחות יחסית מדי לחות רגשי לחות מתמרי לחות אוגרי נתונים	לחות יחסית	0 °C to 10 °C		ASTM-E-104-85 NIS 19 OIML R121 Manufacturer instructions WI-C046	Chilled mirror hygrometer. היגרומטר מד נקודת טל. Humidity and temperature controlled chamber. תא מבוקר לחות וטמפרטורה.
528	A	P			(5% rh to 50%] rh	1.0 % rh		
529	A	P			(50% rh 80%] rh	1.4 % rh		
				לחות יחסית	10 °C to 45 °C			
530	A	P			(5% rh to 50%] rh	0.8 % rh		
531	A	P			(50% rh 80%] rh	1.1 % rh		
532	A	P			(80% rh 95%] rh	1.3 % rh		
				לחות יחסית	45 °C to 60 °C			
533	A	P			(5% rh to 50%] rh	0.8 % rh		
534	A	P			(50% rh to 80%] rh	1.0 % rh		
			Relative humidity RH probes RH chambers RH meters לחות יחסית רגשי לחות תאי לחת מדי לחות	לחות יחסית	0 °C to 10 °C			Humidity sensors, Humidity and temperature controlled Calibrator
535	A	T			[5% rh to 80%] rh	2.0 % rh		
				לחות יחסית	10 °C to 45 °C			
536	A	T			[5% rh to 95%] rh	2.0 % rh		
537				לחות יחסית	45 °C to 60 °C			
538	A	T			[5% rh to 80%] rh	2.0 % rh		

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Calibration – Physical Quantities - Humidity						***כיול – גדלים פיזיקליים - לחות***		
			Relative humidity	לחות יחסית	23°C ± 2 °C			Salt solutions in ampoules as humidity standards.
539	A	P;T	RH probes		11.3% rh	0.5% rh		
540	A	P;T	לחות יחסית		35% rh	0.7% rh		
541	A	P;T	רגשי לחות		50% rh	1.1% rh		
542	A	P;T			75% rh	1.5% rh		
543	A	P;T			80% rh	1.5% rh		
544	A	P;T			95% rh	1.6% rh		
545	A	P;T	Dew point	נקודת טל	[- 40 ^{0}C to - 30] ^{0}C	0.35 ^{0}C		Chilled mirror hygrometer היגרומטר מד נקודת טל.
546	A	P;T	RH meters		[- 30 ^{0}C to + 50] ^{0}C	0.2 ^{0}C		
547	A	P;T	RH transducers לחות יחסית מדי לחות מתמרי לחות		(50 ^{0}C to 60] ^{0}C	0.25 ^{0}C		

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Item	Scope Type	Site	Measurand Instrument, Gauge		Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Documents	Remarks
Calibration – Physical Quantities - Mass								***כיול – גדלים פיזיקליים - מסה***
5	A	P	Mass Weights	מסה משקולות	20000 g	40 mg	OIML R 111-1 OIML R 52 ASTM-E-617	מאזני השוואה Calibration can be given in other units as required. Intermediate value can be calibrated with an uncertainty interpolated from the next higher and lower values in the table.
5	A	P			10000 g	5.1 mg		
5	A	P			5000 g	2.9 mg		
5	A	P			2000 g	0.63 mg		
5	A	P			1000 g	0.50 mg		
5	A	P			500 g	0.35 mg		
5	A	P			200 g	0.080 mg		
5	A	P			100 g	0.049 mg		
5	A	P			50 g	0.030 mg		
5	A	P			20 g	0.021 mg		
5	A	P			10 g	0.020 mg		
5	A	P			5 g	0.0081 mg		
5	A	P			2 g	0.0063 mg		
5	A	P			1 g	0.0054 mg		
5	A	P			0.5 g	0.0044 mg		
5	A	P			0.2 g	0.0035 mg		

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Calibration – Physical Quantities - Mass								***כיול – גדלים פיזיקליים - מסה***
5	A	P			0.1 g	0.0029 mg		
5	A	P			0.05 g	0.0026 mg		
5	A	P			0.02 g	0.0025 mg		
5	A	P			0.01 g	0.0020 mg		
5	A	P			0.005 g	0.0020 mg		
5	A	P			0.002 g	0.0020 mg		
5	A	P			0.001 g	0.0020 mg		
5	A	P			[0.5 g to 200 g]	0.1 mg		מאזני השוואה
5	A	P			(200 g to 1 kg]	0.5 mg		
5	A	P			(1 kg to 5 kg]	20 mg		
5	A	P			(5 kg to 10 kg]	30 mg		
5	A	P			(10 kg to 29 kg]	60 mg		

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Calibration – Physical Quantities - Mass							***כיול – גדלים פיזיקליים - מסה***
5	A	P;T	Non automatic weighing instruments Resolution 0.001 mg and less מאזניים לא אוטומטיים כושר הפרדה 0.001 mg או נמוך.	(Up to 10 mg]	2.5 µg	OIML R76 Manufacturer instructions WI-C044	**1.** Uncertainties depend on the performance of the weighting machine under calibration. **2.** Available weights are: OIML Class E2 from 1 mg to 2 kg, OIML Class F1 from 1 mg to 5 kg, OIML Class F2 from 1 mg to 5 kg, OIML Class M1 from 1 mg to 20 kg, OIML Class M2 from 5 kg to 20 kg, test weights 2 × 500 kg. OIML Class E1weights can be provided on demand.
5	A	P;T		(10 mg to 500 mg]	5 µg		
5	A	P;T		(500 mg to 2 g]	7 µg		
5	A	P;T		(2 g to 5 g]	10 µg		
5	A	P;T		(5 g to 20 g]	25 µg		
5	A	P;T		(20 g to 50 g]	30 µg		
5	A	P;T	Non automatic weighing instruments Resolution 0.01 mg מאזניים לא אוטומטיים כושר הפרדה 0.01 mg.	(Up to 5 g]	15 µg		
5	A	P;T		(5 g to 50 g]	40 µg		
5	A	P;T		(50 g to 250 g]	80 µg		
5	A	P;T	Non automatic weighing instruments Resolution 0.1 mg מאזניים לא אוטומטיים כושר הפרדה 0.1 mg	(Up to 50 g]	0.1 mg		
5	A	P;T		(50 g to 250 g]	0.2 mg		
5	A	P;T		(250 g to 520 g]	0.4 mg		
5	A	P;T	Non automatic weighing instruments Resolution 0.001 g מאזניים לא אוטומטיים כושר הפרדה 0.001 g	(Up to 620 g]	2 mg		
5	A	P;T		(620 g – 2 kg]	3 mg		
5	A	P;T	Non automatic weighing instruments Resolution 0.01 g מאזניים כושר הפרדה 0.01 g.	(Up – 5.1 kg]	0.01 g		
5	A	P;T		(5.1 kg – 12.1 kg]	0.02 g		

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Calibration – Physical Quantities - Mass						***כיול – גדלים פיזיקליים - מסה***		
5	A	P;T	Non automatic weighing instruments Resolution 0.1 g	מאזניים לא אוטומטיים כושר הפרדה 0.1 g	(0 to 8.1 kg]	0.1 g		
5	A	P;T			(8.1 kg to 32 kg]	0.2 g		
5	A	P;T			(32 kg to 64 kg]	0.4 g		
5	A	P;T	Non automatic weighing instruments Resolution 0.001 kg	מאזניים לא אוטומטיים כושר הפרדה 0.001 kg	(Up to 50 kg]	1 g		
5	A	P;T			(50 kg to 150 kg]	2 g		
5	A	P;T	Non automatic weighing instruments Resolution 0.01 kg	מאזניים לא אוטומטיים כושר הפרדה 0.01 kg	(Up to 200 kg]	10 g		
5	A	P;T			(200 kg to 500 kg]	20 g		
5	A	P;T	Non automatic weighing instruments Resolution 0.1 kg	מאזניים לא אוטומטיים כושר הפרדה 0.1 kg	(Up 0 to 1000 kg]	0.1 kg		
6	A	P;T			(1000 kg to 2000 kg]	0.2 kg		
6	A	P;T	Non automatic weighing instruments Resolution 0.5 kg	מאזניים לא אוטומטיים כושר הפרדה 0.5 kg	(Up to 10000 kg]	0.5 kg		

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Calibration – Physical Quantities - Pressure					***כיול - גדלים פיזיקליים – לחץ***			
602	A	P;T	Pneumatic pressure, Gauge. Pressure indicating instruments and gauges Differential pressure	לחץ פניאומאטי, יחסי מדידי לחץ פניאומאטיים לחץ הפרשי	[-1.25 kPa to 1.25 kPa]	0.7 Pa/kPa OR + 0.05 Pa	OIML-R 101 Euramet cg 17 Manufacturer instructions WI-C047	Druck 610LP 1 Pa/kPa = 0.1%
603	A	P	Pneumatic pressure Absolute. Pressure indicating instruments and gauges	לחץ פניאומאטי, אבסולוטי מדידי לחץ פניאומאטיים	[1.6 kPa to 7 MPa]	0.10 Pa/kPa OR + 1 Pa		Budenberg 580H Ruska 2465-754
604	A	P	Pneumatic pressure, Gauge. Pressure indicating instruments and gauges	לחץ פניאומאטי, יחסי מדידי לחץ פניאומאטיים	[1.6 kPa to 7 MPa]	0.10 Pa/kPa OR + 0.35 Pa		Ruska 2465-754
605	A	P	Pneumatic pressure, Dead weight tester. Effective area of pneumatic dead weight tester piston	לחץ פניאומאטי כיול שטח אפקטיבי של בוכנת מאזני לחץ פניאומאטיים	[1.6 kPa to 7 MPa]	0.10 Pa/kPa OR + 0.35 Pa	Euramet cg 3 Manufacturer instructions WI-C068	Ruska 2465-754 Dead weight tester to be supplied with its mass set Calibration by means of cross float method
606	A	P	Hydraulic pressure, (gauge) Pressure indicating instruments and gauges	לחץ הידראולי מדידי לחץ	[0.6 MPa to 121 MPa]	0.20 Pa/kPa	OIML-R 101 Euramet cg 17 Manufacturer instructions WI-C068	DH-Budenberg 580HX

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Calibration – Physical Quantities - Pressure						*כיול - גדלים פיזיקליים – לחץ*		
607	A	P	Hydraulic pressure, Dead weight tester. Effective area of hydraulic dead weight tester piston	לחץ הידראולי כיול שטח אפקטיבי של בוכנת מאזני לחץ הידראוליים	[0.6 MPa to 121 MPa]	0.20 Pa/kPa	Euramet cg 3 Manufacturer instructions WI-C068	DH-Budenberg 580HX Dead weight tester to be supplied with its mass set Calibration by means of cross float method
608	A	T	Pneumatic pressure Absolute Pressure indicating instruments and gauges	לחץ פניאומאטי, אבסולוטי מדידי לחץ פניאומאטיים	[1.6 kPa to 0.7 MPa]	1.5 Pa/kPa	OIML-R 101 Euramet cg 17 BHS-IP2 ISO 81060-2 Manufacturer instructions WI-C047	Druck 610 Druck 603 Druck 104 CONTEC MS200
609	A	T	Pneumatic pressure Gauge Pressure indicating instruments and gauges	לחץ פניאומאטי, יחסי מדידי לחץ פניאומאטיים	[1.6 kPa to 7 MPa]	1.0 Pa/kPa		
610	A	T	Hydraulic pressure (gauge) Pressure indicating instruments and gauges	לחץ הידראולי מדידי לחץ	[0.6 MPa to 70 MPa]	1.0 Pa/kPa		

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Calibration – Physical Quantities - Temperature						***כיול – גדלים פיזיקליים - טמפרטורה***		
611	A	P	Liquid in glass thermometers	תרמומטרים נוזל בזכוכית	[- 80 ºC to – 30 ºC]	0.15 ºC	ISO 1770 ISO 1771 ISO 386 JIS 7411 JIS 7412 JIS 7542 ASTM E563 ASTM E77 BS 593 BS 1704 Manufacturer instructionsWI-C065	אמבטיות כיול תרמומטר אב PRT
612	A	P			(- 30 ºC to 0 ºC]	0.1 ºC		
613	A	P			0 ºC	0.01 ºC		
614	A	P			(0 ºC to 250 ºC]	0.08 ºC		
615	A	P			(250 ºC to 550 ºC]	0.5°C		
616	A	T			[-40 ºC to 150 ºC]	1.0 ºC		
617	A	T			0 ºC	0.05 ºC		
618	A	T			(150 ºC to 250 ºC]	2.0 ºC		
619	A	P	PRT Measurement by comparison	גששי טמפרטורה התנגדות	-196 ºC	0.02 ºC	ASTM-E-1137 ASTM-E-644 IEC 751 ITS-90 Manufacturer instructions WI-C065	Liquid nitrogen
620					[- 90 ºC to -80 ºC)	0. 2 ºC		PRT may calibrated with its indicator. The uncertainty will be dependent on the indicator performance.
621	A	P			[- 80 ºC to 250 ºC]	0.02 ºC		
622	A	P			(250 ºC to 550 ºC]	0.05 ºC		
623	A	P			(550 ºC to 661 ºC]	0.3 ºC		
624	A	P			0.01 ºC	0.006 ºC		By WTP
625	A	T	PRT Measurement by comparison	גששי טמפרטורה התנגדות	-196 ºC	0.1 ºC		Liquid nitrogen
626	A	T			[- 90 ºC to – 40 ºC]	0.3 ºC		
627	A	T			[- 40 ºC to 140 ºC]	0.1 ºC		

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Calibration – Physical Quantities - Temperature						*כיול – גדלים פיזיקליים - טמפרטורה*		
628	A	T			(140 ºC to 250 ºC]	0.3 ºC		
629	A	T			(250 ºC to 650 ºC]	0.5 ºC		
630	A	P	TC base metal Measurement by comparison	צמדים תרמיים מתכות בסיסיות	-196 ºC	0.14 ºC	ASTM-E-230 ASTM-E-220 ITS-90 Manufacturer instructions WI-C065	Liquid nitrogen TC may calibrated with its indicator. The uncertainty will be dependent on the indicator performance.
631					[- 90 ºC to -80 ºC)	0. 2 ºC		
632	A	P			[- 90 ºC to 250 ºC]	0.14 ºC		
633	A	P			(250 ºC to 550 ºC]	0.4 ºC		
634	A	P			(550 ºC to 1100 ºC]	1 ºC		
635	A	T			-196 ºC	0.3 ºC		
636	A	T			[- 80 ºC to -40 ºC]	0.5 ºC		
637					[- 40 ºC to 250 ºC]	0.3 ºC		
638	A	T			(250 ºC to 550 ºC]	0.5 ºC		
639	A	T			(550 ºC to 1100 ºC]	1.5 ºC		
640	A	P	TC noble metal Measurement by comparison	צמדים תרמיים מתכות אצילות	[- 50 ºC to 550 ºC]	0.4 ºC	ASTM-E-230 ASTM-E-220 ITS-90 Manufacturer instructions WI-C065	TC may calibrated with its indicator. The uncertainty will be dependent on the indicator performance.
641	A	P			(550 ºC to 1100 ºC]	1 ºC		
642	A	T			[- 50 ºC to 250 ºC]	0.5 ºC		
643	A	T			(250 ºC to 550 ºC]	0.7 ºC		
644	A	T			(550 ºC to 1100 ºC]	1.5 ºC		
645	A	P;T	Freezing chambers Including uniformity	מקפיאים כולל בדיקת אחידות	[-90 ºC to –50 ºC]	1 ºC	DKD-R-5-7 Manufacturer instructions WI-C062	TC, PRT, Data logger

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Calibration – Physical Quantities - Temperature					***כיול – גדלים פיזיקליים - טמפרטורה***			
646	A	P;T	Freezers, Incubators, Autoclaves Including uniformity	מקפיאים, אינקובטורים אוטוקלבים כולל בדיקת אחידות	[-50 ºC to 151 ºC]	0.5 ºC	DKD-R-5-7 DIN 12880 Manufacturer instructions WI-C062	TC, PRT, Data logger
647	A	P;T	Furnaces Including uniformity	תנורים כולל בדיקת אחידות	[50 ºC to 300 ºC]	0.7 ºC	DKD-R-5-7 DIN 12880 Manufacturer instructions WI-C062	TC, PRT, Data logger
648	A	P;T			(300 ºC to 550 ºC]	1 ºC		
649	A	P;T			(550 ºC to 1100 ºC]	2.5 ºC		
650	A	P;T	Bathes Including uniformity	אמבט כולל בדיקת אחידות	[-196 ºC to 251 ºC]	0.03 ºC	Manufacturer instructions WI-C062	SPRT, PRT
651	A	P;T			(251 ºC to 550 ºC]	0.09 ºC		
652	A	P	Dry block calibrator	תנור בלוק יבש	[–110 ºC to 300 ºC]	0.05 ºC	EURAMET cg-13 Manufacturer instructions WI-C062	PRT
653	A	P			(300 ºC to 650 ºC]	0.3 ºC		
654	A	P;T	Tube furnace Including uniformity	תנור כיול צינורי כולל בדיקת אחידות	[300 ºC to 660 ºC]	0.2 ºC	Manufacturer instructions WI-C062	
655	A	P;T			(660 ºC to 1100 ºC]	1.2 ºC		
656	A	P;T	Temperature indicators, controllers, recorders and simulators for the resistance sensors	מדי, רשמי ומדמי טמפרטורה עבור מדי התנגדות	-200 °C to 800 °C	0.01 °C	EURAMET cg-11 Manufacturer instructions WI-C067	Calibration by means of electrical calibration,
657	A	P	Temperature indicators, controllers, recorders and simulators for the base metal thermocouples	מדי, רשמי ומדמי טמפרטורה עבור צמדים תרמיים מתכות בסיסיות	-200 °C to 1380 °C	0.2 °C	EURAMET cg-11 Manufacturer instructions WI-C067	Calibration by means of electrical calibration, including cold junction compensation
658	A	T			-200 °C to 1380 °C	0.4 °C		

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Calibration – Physical Quantities - Temperature						***כיול – גדלים פיזיקליים - טמפרטורה***		
659	A	P	Temperature indicators, controllers, recorders and simulators for the noble metal thermocouples	מדי, רשמי ומדמי טמפרטורה עבור צמדים תרמיים מתכות אצילות	0 °C to 500 °C	0.5 °C	EURAMET cg-11 Manufacturer instructions WI-C067	Calibration by means of electrical calibration, including cold junction compensation
660	A	P			500 °C to 1800 °C	0.3 °C		
661	A	T			0 °C to 500 °C	0.9 °C		
662	A	T			500 °C to 1800 °C	0.6 °C		
663	A	P	Temperature, Infrared Thermometers,	טמפרטורה מדי טמפרטורת קרינה	[35 °C to 100 °C]	0.6 °C	ASTM E2847 Manufacturer instructions WI-C080	IR Calibrator
664	A	P			(100 °C to 200 °C]	1.0 °C		
665	A	P			(200 °C to 350 °C]	1.7 °C		
666	A	P			(350 °C to 500 °C]	2.5 °C		

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Calibration – Small (up to 2L) Volume Volumetric Instruments						***כיול – כיול מכשירים וולומֶטְרִיים – נפחים קטנים עד 2 ליטר***		
			Liquid volume, Piston-operated volumetric apparatus	נפח נוזלים כיול מכשירים וולומטריים בהנע בוכנה	Nominal value		ISO 8655-Part 1,2,3,4,5,6 ISO/TR 20461 Manufacturer instructions WI-C074	מתקן נפח מופעל בוכנה POVA Intermediate volumes may be calibrated with uncertainty as for the higher volume value
667	A	P			1µl	0.030 µl		
668	A	P			2 µl	0.040 µl		
669	A	P			5 µl	0.050 µl		
670	A	P			10 µl	0.060 µl		
671	A	P			20 µl	0.080 µl		
672	A	P			50 µl	0.21 µl		
673	A	P			100 µl	0.27 µl		
674	A	P			200 µl	0.72 µl		
675	A	P			500 µl	1.3 µl		
676	A	P			1000 µl	1.8 µl		
677	A	P			2000 µl	5.4 µl		
678	A	P			5000 µl	9.6 µl		
679	A	P			10000 µl	15 µl		
680	A	P			20000 µl	20 µl		
681	A	P			25000 µl	25 µl		
682	A	P			50000 µl	35 µl		